

Notice of References Cited			Application/Control No. 10/538,302	Applicant(s)/Patent Under Reexamination MIYAKE ET AL.	
			Examiner Kezhen Shen	Art Unit 2627	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,819,103 A	10-1998	Endoh et al.	710/1
*	B	US-5,918,222 A	06-1999	Fukui et al.	707/1
*	C	US-6,034,832 A	03-2000	Ichimura et al.	360/60
*	D	US-2001/0028603 A1	10-2001	Shimazu, Hideo	368/10
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2000-076801	03-2000	Japan	Oowa Tae	G11B 20/10
	O	JP 2002-314917	10-2002	Japan	Watanabe Kenji	G11B 20/10
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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